Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances \leq 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mM)]·[$\sqrt{f}(GHZ)$] ≤ 3.0 for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BLE:

Modulation	Channel Freq. (GHz)	Conducte d power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
BLE(1M)	2.402	-4.95	0.32	-5±1	-4	0.40	<5	0.12340	3.00	YES
	2.440	-5.1	0.31	-5±1	-4	0.40	<5	0.12437	3.00	YES
	2.480	-5.68	0.27	-6±1	-5	0.32	<5	0.09960	3.00	YES
BLE(2M)	2.402	-4.94	0.32	-5±1	-4	0.40	<5	0.12340	3.00	YES
	2.440	-5.1	0.31	-5±1	-4	0.40	<5	0.12437	3.00	YES
	2.480	-5.64	0.27	-6±1	-5	0.32	<5	0.09960	3.00	YES

SRD 2.4G

Modulation	Channel Freq. (GHz)	Conducte d power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
	2.402	-1.05	0.79	-2±1	-1	0.79	<5	0.24622	3.00	YES
GFSK	2.446	-2.11	0.62	-2±1	-1	0.79	<5	0.24846	3.00	YES
	2.479	-2.62	0.55	-3±1	-2	0.63	<5	0.19869	3.00	YES

Note: This product does not support the requirements under 2.4G multiple sources. **Conclusion:**

For the max result : $0.24846 \le 3.0$ for 1g SAR, SAR is not required.

Alex Li

Signature:

Date: 6/19/2024

NAME AND TITLE (Please print or type): Alex li /Manager

COMPANY (Please print or type): Shenzhen NTEK Testing Technology Co., Ltd./ 1/F, Building E, Fenda Science Park, Sanwei Community, Xixiang Street Bao'an District, Shenzhen P.R. China.